Revision History

Revision 0.1 (Nov. 2011) -First release.

2Gb (16M×8Bank×16) Double DATA RATE 2 SDRAM

Features

- JEDEC Standard VDD/VDDQ = 1.8V±0.1V.
- All inputs and outputs are compatible with SSTL_18 interface.
- Fully differential clock inputs (CK, /CK) operation.
- Eight Banks
- Posted CAS
- Bust length: 4 and 8.
- Programmable CAS Latency (CL): 5, 7
- Programmable Additive Latency (AL): 0, 1, 2, 3, 4, 5 & 6.
- Write Latency (WL) =Read Latency (RL) -1.
- Read Latency (RL) = Programmable Additive Latency (AL) + CAS Latency (CL)
- Bi-directional Differential Data Strobe (DQS).
- Data inputs on DQS centers when write.
- Data outputs on DQS, /DQS edges when read.
- On chip DLL align DQ, DQS and /DQS transition with CK transition.
- DM mask write data-in at the both rising and falling edges of the data strobe.
- Sequential & Interleaved Burst type available.
- Off-Chip Driver (OCD) Impedance Adjustment
- On Die Termination (ODT)
- Auto Refresh and Self Refresh
- 8,192 Refresh Cycles / 64ms
- Average Refresh Period 7.8us
- RoHS Compliance
- High Temperature Self-Refresh rate enable

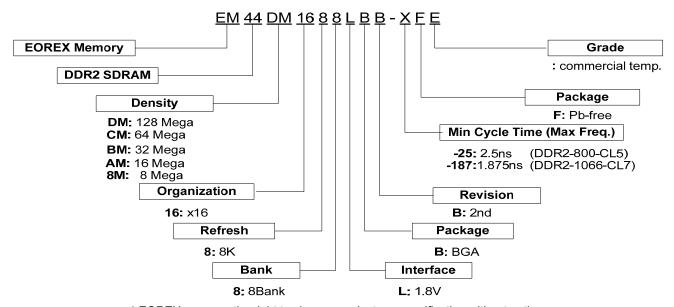
Description

The EM44DM1688LBB is a high speed Double Date Rate 2 (DDR2) Synchronous DRAM fabricated with ultra high performance CMOS process containing 2,147,483,648 bits which organized as 16Mbits x 8 banks by 16 bits. This synchronous device achieves high speed double-data-rate transfer rates of up to 1066 Mb/sec/pin (DDR2-1066) for general applications. The chip is designed to comply with the following key DDR2 SDRAM features: (1) posted CAS with additive latency, (2) write latency = read latency -1, (3) Off-Chip Driver (OCD) impedance adjustment and On Die Termination (4) normal and weak strength data output driver. All of the control and address inputs are synchronized with a pair of externally supplied differential clocks. Inputs are latched at the cross point of differential clocks (CK rising and /CK falling). All I/Os are synchronized with a pair of bidirectional strobes (DQS and /DQS) in a source synchronous fashion. The address bus is used to convey row, column and bank address information in a /RAS and /CAS multiplexing style. The 2Gb DDR2 device operates with a single power supply: $1.8V \pm 0.1V$ VDD and VDDQ. Available package: FBGA-84Ball (with 0.8mm x 0.8mm ball pitch)

Ordering Information

Part No	Organization	Max. Freq	Package	Grade	Pb
EM44DM1688LBB-25F	128M X 16	DDR2-800-CL5	FBGA-84B	Commercial	Free
EM44DM1688LBB-187F	128M X 16	DDR2-1066-CL7	FBGA-84B	Commercial	Free

Parts Naming Rule



^{*} EOREX reserves the right to change products or specification without notice.



Pin Assignment: Top View

1	2	3		7	8	9
VDD	NC	VSS	Α	VSSQ	/UDQS	VDDQ
DQ14	VSSQ	UDM	В	UDQS	VSSQ	DQ15
VDDQ	DQ9	VDDQ	С	VDDQ	DQ8	VDDQ
DQ12	VSSQ	DQ11	D	DQ10	VSSQ	DQ13
VDD	NC	VSS	Е	VSSQ	/LDQS	VDDQ
DQ6	VSSQ	LDM	F	LDQS	VSSQ	DQ7
VDDQ	DQ1	VDDQ	G	VDDQ	DQ0	VDDQ
DQ4	VSSQ	DQ3	Н	DQ2	VSSQ	DQ5
VDDL	VREF	VSS	J	VSSDL	СК	VDD
	CKE	/WE	K	/RAS	/CK	ODT
BA2	BA0	BA1	L	/CAS	/CS	
	A10/AP	A1	М	A2	A0	VDD
vss	А3	A5	N	A6	A4	
	A7	A9	Р	A11	A8	vss
VDD	A12	NC	R	NC	A13	
VDD						

84Ball FBGA

Note: VDDL and VSSDL are power and ground for the DLL.

Pin Description (Simplified)

Pin	Name	Function		
	'	(System Clock)		
J8,K8	CK,/CK	CK and CK are differential clock inputs. All address and control input signals are sampled on the crossing of the positive edge of CK and negative edge of CK. Output (read) data is referenced to the crossings of CK and CK (both directions of crossing).		
		(Chip Select)		
L8	/CS	All commands are masked when CS is registered HIGH. CS provides for external Rank selection on systems with multiple Ranks. CS is considered part of the command code.		
		(Clock Enable)		
K2	CKE	CKE high activates and CKE low deactivates internal clock signals and device input buffers and output drivers. Taking CKE low provides Precharge Power-Down and Self- Refresh operation (all banks idle), or Active Power-Down (row Active in any bank). CKE is synchronous for power down entry and exit and for Self-Refresh entry. CKE is asynchronous for Self-Refresh exit. CKE must be maintained high throughout read and write accesses. Input buffers, excluding CK, /CK, ODT and CKE are disabled during Power Down. Input buffers, excluding CKE are disabled during Self-Refresh.		
		(Address)		
M8,M3,M7,N2, N8,N3,N7,P2, P8,P3,M2,P7, R2,R8	A0~A13	Provided the row address (RA0 – RA13) for Active commands and the column address (CA0-CA9) and Auto Precharge bit for Read/Write commands to select one location out of the memory array in the respective bank. A10 is sampled during a Precharge command to determine whether the Precharge applies to one bank (A10 LOW) or all banks (A10 HIGH). If only one bank is to be precharged, the bank is selected by BA0, BA1 & BA2. The address inputs also provide the op-code during Mode Register Set commands.		
		(Bank Address)		
L2,L3,L1	BA0, BA1,BA2	BA0 – BA2 define to which bank an Active, Read, Write or Precharge command is being applied. Bank address also determines if the mode register or extended mode register is to be accessed during a MRS or EMRS cycle.		
		(On Die Termination)		
К9	ODT	ODT (registered HIGH) enables termination resistance internal to the DDR2 SDRAM. When enabled, ODT is applied to each DQ, UDQS/UDQS, LDQS/LDQS, UDM, and LDM signal. The ODT pin will be ignored if the Extended Mode Register EMRS(1) is programmed to disable ODT.		
		(Command Inputs)		
K7, L7, K3	/RAS,/CAS,/WE	/RAS, /CAS and /WE (along with /CS) define the command being entered.		

Pin Description (Continued)

B7,A8,F7,E8	UDQS,/UDQS , LDQS,/LDQS	(Data Strobe) Output with read data, input with write data. Edge-aligned with read data, centered in write data. LDQS corresponds to the data on DQ0-DQ7; UDQS corresponds to the data on DQ8-DQ15. The data strobes LDQS and UDQS may be used in single ended mode or paired with optional complementary signals /LDQS and /UDQS to provide differential pair signaling to the system during both reads and writes. An EMRS(1) control bit enables or disables all complementary data strobe signals. In this data sheet, "differential DQS signals" refers to A10 = 0 of EMRS(1) using LDQS/LDQS and UDQS/UDQS. "single-ended DQS signals" refers to A10 = 1 of EMRS(1) using LDQS and UDQS.
B3,F3	UDM,LDM	(Input Data Mask) DM is an input mask signal for write data. Input data is masked when DM is sampled HIGH coincident with that input data during a Write access. DM is sampled on both edges of DQS. Although DM pins are input only, the DM loading matches the DQ and DQS loading.
G8,G2,H7,H3, H1,H9,F1,F9, C8,C2,D7,D3, D1, D9,B1,B9	DQ0~15	(Data Input/Output) Data inputs and outputs are on the same pin.
A1,E1,J9,M9, R1/A3,E3,J3, N1,P9	VDD/VSS	(Power Supply/Ground) VDD and VSS are power supply for internal circuits.
A9,C1,C3,C7, C9,E9,G1,G3, G7,G9/A7,B2, B8,D2,D8,E7, F2,F8,H2,H8	VDDQ/VSSQ	(DQ Power Supply/DQ Ground) VDDQ and VSSQ are power supply for the output buffers.
J1/J7	VDDL/VSSDL	(DLL Power Supply/DLL Ground) VDDL and VSSDL are power supply for DLL circuits
J2	VREF	(Reference Voltage) SSTL_1.8 reference voltage
A2,E2,R3,R7	NC	(No Connection) No internal electrical connection is present.

Absolute Maximum Rating

Symbol	Item	Rati	Rating	
Vin, Vout	Input, Output Voltage	-0.5 ~	+2.3	V
V _{DD}	Power Supply Voltage	-1.0 ~	-1.0 ~ +2.3	
VDDQ	Power Supply Voltage	-0.5 ~ +2.3		V
V _{DDL}	DLL Power Supply Voltage	-0.5 ~	-0.5 ~ +2.3	
Тор	Operating Temperature Range	Commercial 0 ~ +70		°C
Тѕтс	Storage Temperature Range	-55 ~ +100		°C
PD	Power Dissipation	1	1	

Note: Caution Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

Recommended DC Operating Conditions (T_A=-0°C ~+70°C)

Symbol	Parameter	Min.	Тур.	Max.	Units
V _{DD}	Power Supply Voltage	1.7	1.8	1.9	V
V _{DDL}	Power Supply for DLL Voltage	1.7	1.8	1.9	V
VDDQ	Power Supply for I/O Voltage	1.7	1.8	1.9	V
VREF	I/O Reference Voltage	0.49 V _{DDQ}	$0.50V_{DDQ}$	0.51 VDDQ	V
VTT	I/O Termination Voltage	VREF-0.04	VREF	V _{REF} +0.04	V
VID	DC Differential Input Voltage	-0.3	-	VREF-0.15	V
VIH	Input Logic High Voltage	V _{REF} +0.125	-	V _{DDQ} +0.3	V
VIL	Input Logic Low Voltage	-0.3	-	VREF-0.125	V

Recommended DC Operating Conditions

 $(V_{DD}=1.8V\pm0.1V)$

Symbol Parameter		Test Conditions	-187(1066)	-25(800)	Units
Syllibol	Parameter	Test Conditions	Ма	X	Ullits
I _{DD1}	Operating Current (Note 1)	IOUT = 0mA BL = 4, CL = CL(IDD), AL = 0 tCK = tCK(IDD), tRC = tRC (IDD) tRAS = tRASmin(IDD), tRCD = tRCD(IDD) CKE=HIGH CS=HIGH between valid commands Address bus inputs are SWITCHING Data pattern is same as IDD4W	140	120	mA
IDD2P	Precharge Standby Current in Power Down Mode	All banks idle tCK = tCK(IDD), CKE is LOW Other control and address bus inputs are STABLE Data bus inputs are FLOATING	12	12	mA
Idd2n	Precharge Standby Current in NON-power down mode All banks idle	All banks idle tCK = tCK(IDD), CKE is HIGH, CS is HIGH Other control and address bus inputs are SWITCHING Data bus inputs are SWITCHING	70	60	mA
IDD3P	Active Standby Current in Power Down Mode (A12=0)	All banks open tCK = tCK(IDD), CKE is LOW Other control and address bus inputs are	35	30	mA
I _{DD3P}	Active Standby Current in Power Down Mode (A12=1)	STABLE Data bus inputs are FLOATING	25	25	mA
lddзn	Active Standby Current in Non-power Down Mode	All banks open tCK = tCK(IDD), tRAS = tRASmax(IDD) tRP = tRP(IDD), CKE is HIGH CS is HIGH between valid commands Other control and address bus inputs are SWITCHING Data bus inputs are SWITCHING	80	70	mA
IDD4W	Operating Current (Burst	All banks open, Continuous burst writes BL = 4, CL = CL(IDD), AL = 0 tCK = tCK(IDD), tRAS = tRASmax(IDD) tRP = tRP(IDD), CKE is HIGH	230	200	mA
IDD4R	Mode) (Note 2)	CS is HIGH between valid commands Address bus inputs are SWITCHING Data bus inputs are SWITCHING	230 200		
IDD5	Refresh Current (Note 3)	tCK = tCK(IDD) Refresh command at every tRFC(IDD) interval CKE is HIGH, CS is HIGH between valid commands Other control and address bus inputs are SWITCHING Data bus inputs are SWITCHING	140	130	mA
IDD6	Self Refresh Current	CK and CK at 0 V, CKE 0.2 V Other control and address bus inputs are FLOATING, Data bus inputs are FLOATING	10	10	mA
I _{DD7}	Operating Current	All bank interleaving reads IOUT = 0mA, BL = 4, CL = CL(IDD) AL = tRCD(IDD) - 1 x tCK(IDD) tCK = tCK(IDD), tRC = tRC(IDD) tRRD = tRRD(IDD), tFAW = tFAW(IDD) tRCD = 1 x tCK(IDD), CKE is HIGH CS is HIGH between valid commands Address bus inputs are STABLE during DESELECTs Data pattern is same as IDD4R	190	170	mA

^{*}All voltages referenced to VSS.

Note 1: IDD1 depends on output loading and cycle rates. (CL=CLmin, AL=0)

Note 2: IDD4 depends on output loading and cycle rates. Input signals SWITCHING

Note 3: Min. of trec (Auto refresh Row Cycle Times) is shown at AC Characteristics.

Recommended DC Operating Conditions (Continued)

Symbol	Parameter	Test Conditions	Min.	Max.	Units
IOH	Output Minimum Source Current	*Note1, 3, 4	-13.4		mA
IOL	Output Minimum Sink Current	*Note2, 3, 4		+13.4	mA

Note1: VDDQ = 1.7 V; VOUT = 1.42 V. (VOUT-VDDQ) / IOH must be less than 21 ohm for values of VOUT between VDDQ and VDDQ - 280 mV.

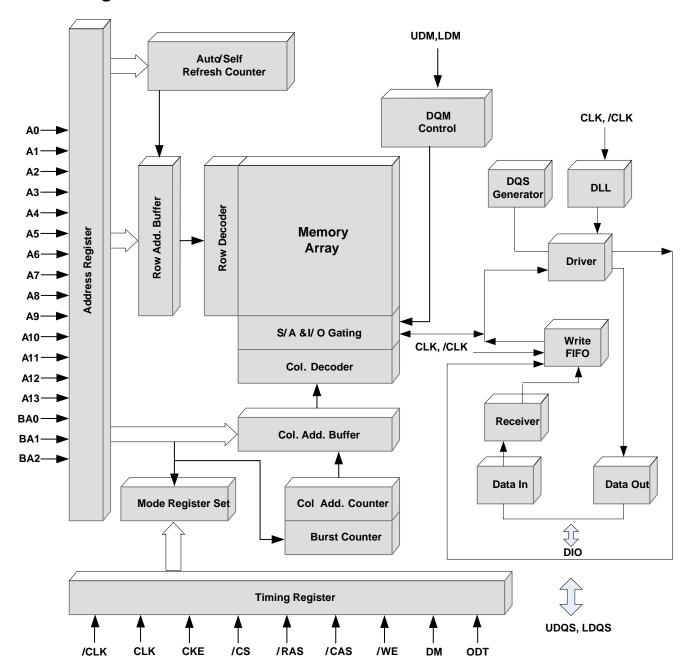
Note2: VDDQ = 1.7 V; VOUT = 280 mV. VOUT / IOL must be less than 21 ohm for values of VOUT between 0V and 280 mV.

Note3: The dc value of VREF applied to the receiving device is set to VTT.

Note4: The values of IOH(dc) and IOL(dc) are based on the conditions given in note 1 and 2. They are used to test drive current capability to ensure VIHmin plus a noise margin and VILmax minus a noise margin are delivered to an SSTL_18 receiver. The actual current values are derived by shifting the desired driver operating points along 21ohm load line to define a convenient current for measurement.

Note5: The VDDQ of the device under test is referenced.

Block Diagram



OCD Default Setting Table

Parameter	Min.	Тур.	Max.	Units
Output Impedance step size for OCD calibration	0	-	1.5	Ω
Pull-up / Pull-down mismatch	0	-	4	Ω
Output Slew Rate	1.5	-	5.0	V/ns

AC Operating Test Conditions

(V_{DD}=1.8V±0.1V)

Symbol	Parameter	Value	Units
V _{SWING} (max.)	Input Signal Maximum Peak to Peak Swing	1.0	٧
SLEW	Input Signal Minimum Slew Rate	1.0	V/ns
V_{REF}	Input Reference Level	$0.5*V_{DDQ}$	V

AC Operating Test Conditions

Symbol	Parameter	Min.	Max.	Units
V_{ID}	AC Differential Input Voltage	0.5	V_{DDQ}	V
V _{IX}	AC Differential Cross Point Input Voltage	0.5*V _{DDQ} -0.175	0.5*V _{DDQ} +0.175	V
V _{OX}	AC Differential Cross Point Output Voltage	0.5*V _{DDQ} -0.125	0.5*V _{DDQ} +0.125	V
V _{IH}	Input Logic High Voltage	V _{REF} +0.2	V_{DDQ} + V_{peak}	V
V _{IL}	Input Logic High Voltage	V_{SSQ} - V_{peak}	V _{REF} -0.2	V



AC Operating Test Characteristics

 $(V_{DD}=1.8V\pm0.1V)$

Table	O. mada ad	Deservator	-187 (DDR2-1066)		-25 (DDR2-800)		Units
todsck DQS output access from CLK,/CLK -350 350 -350 350 ps t_CL, t_CH CL low/high level width 0.48 0.52 0.48 0.52 t _{CK} t_CK Clock Cycle Time 1.875 8 2.5 8 ns t_DS DQ and DM setup time 50 - 50 - ps t_DH DQ and DM hold time 75 - 125 - ps t_DH DQ and DM input pulse width for each input 0.35 - 0.35 - tck t_HZ DATE out high impedance time from CLK,/CLK - t_AC - t_AC - t_AC - t_AC - t_AC - - t_AC -	Symbol	Parameter	Min.	Max.	Min.	Max.	
t _{CL,t} CH CL low/high level width 0.48 0.52 0.48 0.52 t _{CK} t _{CK} Clock Cycle Time 1.875 8 2.5 8 ns t _{DS} DQ and DM setup time 50 - 50 - ps t _{DH} DQ and DM hold time 75 - 125 - ps t _{DH} DQ and DM input pulse width for each input 0.35 - 0.35 - t _{CK} t _{HZ} Data out high impedance time from CLK,/CLK - t _{AC} (max) - t _{AC} (max) ns t _{LZ (DQ)} DQ low impedance time from CLK,/CLK 2*t _{AC} (min) t _{AC} (max) t _{AC} (max) ns t _{LZ (DQS)} DQS,/DQS low impedance time from CLK,/CLK t _{AC} (min) t _{AC} (max) t _{AC} (max) ns t _{DQS} ,/DQS low impedance time from CLK,/CLK t _{AC} (min) t _{AC} (max) ns ns t _{DQS} ,/DQS low impedance time from CLK,/CLK t _{AC} (min) t _{AC} t _{AC} t _{AC} (min) ns ns t _{DSS} , t _{DQS} ,DQS low impedance time from CLK,/CLK t _{AC}	t _{AC}	DQ output access from CLK,/CLK	-350	350	-400	400	ps
t _{CK} Clock Cycle Time 1.875 8 2.5 8 ns t _{DS} DQ and DM setup time 50 - 50 - ps t _{DH} DQ and DM hold time 75 - 125 - ps t _{DHPW} DQ and DM input pulse width for each input 0.35 - 0.35 - t _{CK} t _{LZ} (DQ) Data out high impedance time from CLK,/CLK - t _{AC} (max) - t _{AC} (max) - t _{AC} (max) ns t _{LZ} (DQ) DQ low impedance time from CLK,/CLK 2*t _{AC} (min) (max) t _{AC} (max) t _{AC} t _{AC} (max) t _{AC} t _{AC} t _{AC} t _{AC} (max) ns t _{LZ} (DQS) DQS,/DQS low impedance time from CLK,/CLK t _{AC}	t _{DQSCK}	DQS output access from CLK,/CLK	-350	350	-350	350	ps
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t_{CL}, t_{CH}	CL low/high level width	0.48	0.52	0.48	0.52	t _{CK}
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{CK}	Clock Cycle Time	1.875	8	2.5	8	ns
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{DS}	DQ and DM setup time	50	-	50	-	ps
the text of the te	t _{DH}	DQ and DM hold time	75	-	125	-	ps
tHz CLK/CLK - (max) - (max) ns tLZ (DQ) DQ low impedance time from CLK,/CLK 2*tAC (min) tAC (max) tAC (min) ms tDQSQ DQS low,HQS low impedance time from CLK,/CLK tAC (min) tAC (min) ms ms tQHS DQS sex bow impedance time from CLK,/CLK tAC (min) tAC (min) ms ms tQHS DQS low,HQB impedance time from CLK,/CLK TAC (min) ms ms ms tDQSQ DQS base feather	t _{DIPW}		0.35	-	0.35	-	t _{CK}
$t_{LZ(DO)} DQ \ low \ impedance \ time \ from \ CLK,/CLK \\ t_{LZ(DQS)} DQS,/DQS \ low \ impedance \ time \ from \\ t_{LZ(DQS)} DQS,/DQS \ low \ impedance \ time \ from \\ t_{LZ(DQS)} DQS,/DQS \ low \ impedance \ time \ from \\ CLK,/CLK ms \\ t_{DQSQ} DQS-DQ \ skew \ for \ associated \ DQ \ signal \\ t_{DQSD} Data \ hold \ skew \ factor - 250 - 300 ps \\ t_{DQSS} Write \ command \ to \ first \ latching \ DQS \\ transition -0.25 0.25 -0.25 0.25 t_{CK} \\ t_{DQSL} \ t_{DQSL}$	t _{HZ}		-		-		ns
t _{LZ (DQS)} DQS,/DQS low impedance time from CLK,/CLK t _{AC} (min) t _{AC} (max) t _{AC} (min) t _{AC} (max)	t _{LZ (DQ)}	· ·	2*t _{AC}	· · ·	2*t _{AC}	` ,	ns
t_Lz (DQS) CLK,/CLK (min) (max) (min) (max) ns t_DQSQ DQS-DQ skew for associated DQ signal - 175 - 200 ps t_DHS Data hold skew factor - 250 - 300 ps t_DHS Write command to first latching DQS transition -0.25 0.25 -0.25 0.25 t_CK t_DQSL, t_DGH DQS Low/High input pulse width 0.35 - 0.35 - t_CK t_DSL, t_DSH DQS input valid window 0.20 - 0.20 - t_CK t_MRD Mode Register Set command cycle time 2 - 2 - t_CK t_WPRES Write Preamble setup time 0 - 0 - ns t_WPST Write Postamble 0.4 0.6 0.4 0.6 t_CK t_IS Address/control input setup time (fast slew rate) 0.25 - 0.275 - ns	(,		· · ·	` '	. ,	` '	
t _{DQSQ} DQS-DQ skew for associated DQ signal - 175 - 200 ps t _{QHS} Data hold skew factor - 250 - 300 ps t _{DQSS} Write command to first latching DQS transition -0.25 0.25 -0.25 0.25 t _{CK} t _{DQSL} ,t _{DQSH} DQS Low/High input pulse width 0.35 - 0.35 - t _{CK} t _{DSL} ,t _{DSH} DQS input valid window 0.20 - 0.20 - t _{CK} t _{MRD} Mode Register Set command cycle time 2 - 2 - t _{CK} t _{WPRES} Write Preamble setup time 0 - 0 - ns t _{WPST} Write Postamble 0.4 0.6 0.4 0.6 t _{CK} t _{IS} Address/control input setup time (fast slew rate) 0.175 - 0.20 - ns	t _{LZ (DQS)}		t _{AC}	t _{AC}	t _{AC}	t _{AC}	ns
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$, ,	` ′	` ,	` ,	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$			-	_	-		· ·
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{QHS}		-	250	-	300	ps
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{DQSS}		-0.25	0.25	-0.25	0.25	t _{CK}
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t_{DQSL}, t_{DQSH}	DQS Low/High input pulse width	0.35	-	0.35	-	t _{CK}
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t_{DSL}, t_{DSH}	DQS input valid window	0.20	-	0.20	-	t _{CK}
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{MRD}	Mode Register Set command cycle time	2	-	2	-	t _{CK}
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{WPRES}	Write Preamble setup time	0	-	0	-	ns
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t _{WPRE}	Write Preamble	0.35	-	0.35	-	t _{CK}
t _{IS} slew rate) 0.175 - 0.20 - ns t _{IH} Address/control input hold time (fast slew rate) 0.25 - 0.275 - ns	t _{WPST}	Write Postamble	0.4	0.6	0.4	0.6	t _{CK}
t _{IH} (fast slew rate) 0.25 - 0.275 - ns	t _{IS}		0.175	-	0.20	-	ns
t _{RPRE} Read Preamble 0.9 1.1 0.9 1.1 t _{CK}	t _{IH}	-	0.25	-	0.275	-	ns
	t _{RPRE}	Read Preamble	0.9	1.1	0.9	1.1	t _{CK}

AC Operating Test Characteristics (Continued)

(VDD=1.8V±0.1V)

Cumahad	Darameter	-187 (DD	R2-1066)	-25 (DDI	R2-800)	Units
Symbol	Parameter	Min.	Max.	Min.	Max.	Units
t RPST	Read Postamble	0.4	0.6	0.4	0.6	t cĸ
t ras	Active to Precharge command period	40	70k	40	70k	ns
t RC	Active to Active command period	56.25	-	57.5	-	ns
t RFC	Auto Refresh Row Cycle Time	127.5	-	127.5	-	ns
t RCD	Active to Read or Write delay	12.5	-	15	-	ns
t RP	Precharge command period	12.5	-	15	-	ns
t RRD	Active bank A to B command period	7.5	-	7.5	-	ns
tccd	Column address to column address delay	2	-	2	-	t cĸ
twr	Write recover time	15	-	15	-	ns
t dal	Auto precharge write recovery + precharge time	t _{RP} + t _{WR}	-	t _{RP} + t _{WR}	-	ns
txard	Exit active power-down mode to read command (fast exit)	3	-	2	-	t cĸ
txards	Exit active power-down mode to read command (slow exit)	10-AL	-	8-AL	-	t cĸ
txp	Exit precharge power-down to any non-read command	3	-	2	-	t cĸ
t wtr	Internal write to read command delay	7.5	-	7.5	-	ns
t RTP	Internal read to precharge delay	7.5	-	7.5	-	ns
txsnr	Exit self Refresh to non-read command	t _{RFC} +10	-	t _{RFC} +10	-	ns
txsrd	Exit self Refresh to read command	200	-	200	-	t cĸ
t REFI	Average periodic refresh interval	-	7.8	-	7.8	us
t CKE	CKE minimum pulse width	3	-	3	-	t cĸ
t FAW	Four active to Row active delay (same bank)	35		35		ns
t 01T	OCD drive mode output delay	0	12	0	12	ns

AC Operating Test Characteristics (Continued)

(VDD=1.8V±0.1V)

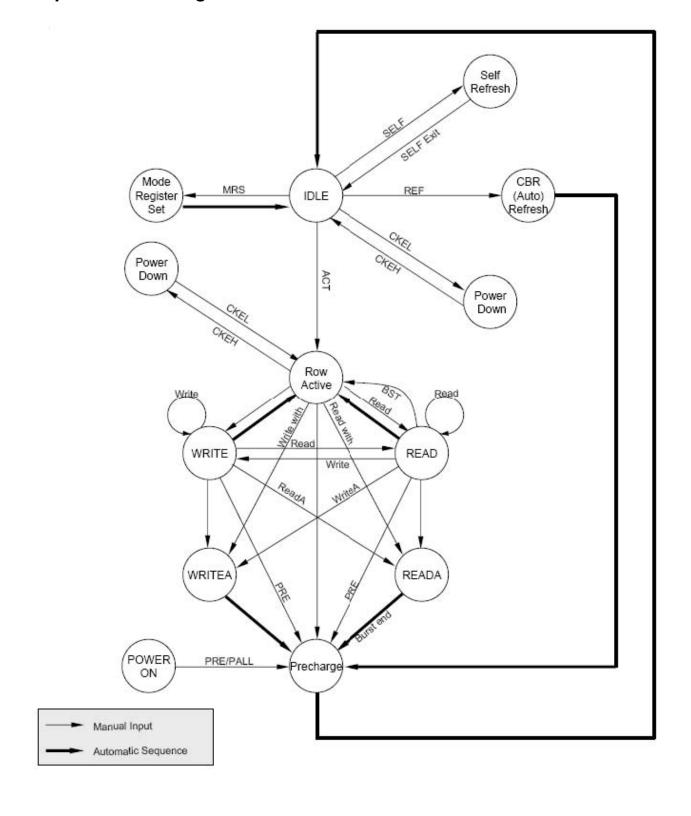
Symbol	Parameter	DDF	R2-800	DDI	R2-1066	Units
Symbol	Farameter	Min.	Max.	Min.	Max.	Ullits
tAOND	ODT turn-on delay	2	-	2	-	tCK
tAOFD	ODT turn-off delay	2.5	-	2.5	-	tCK
tAON	ODT turn-on ^(Note1)	$t_{AC(min.)}$	t _{AC(max)} +0.7	t _{AC(min.)}	t _{AC(max)} +2.575	ns
tAOF	ODT turn-off ^(Note2)	t _{AC(min.)}	t _{AC(max)} +0.6	t _{AC(min.)}	t _{AC(max)} +0.6	ns
tAONPD	ODT turn-on in power-down mode	t _{AC(min.)} +2	2*tCK + t _{AC(max)} +1	t _{AC(min.)} +2	2*tCK + t _{AC(max)} +1	ns
tAOFPD	ODT turn-off in power-down mode	t _{AC(min.)} +2	2.5*tCK + t _{AC(max)} +1	t _{AC(min.)} +2	2.5*tCK + t _{AC(max)} +1	ns
tANPD	ODT to power-down mode entry latency	3	-	2.5	-	tCK
tAXPD	ODT power-down exit latency	8	-	11	-	tCK

Note 1: ODT turn on time min is when the device leaves high impedance and ODT resistance begins to turn on. ODT turn on time max is when the ODT resistance is fully on. Both are measure from t_{AOND} .

Note 2: ODT turn off time min is when the device starts to turn off ODT resistance ODT turn off time max is when the bus is in high impedance. Both are measured from t_{AOFD} .

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Simplified State Diagram



1. Command Truth Table

0	0	Ck	ΚE	/00	/D A O	(0.4.0	0.4/5	BA0	440	440.40
Command	Symbol	n-1	N	/CS	/RAS	/CAS	/WE	~ BA2	A10	A12~A0
Device Deselect	DESL	Н	Х	Н	Χ	Χ	Χ	Χ	Х	Х
No Operation	NOP	Н	Χ	L	Н	Н	Н	Х	Х	Х
Read	READ	Н	Н	L	Н	L	Н	V	L	V
Read with Auto Pre-charge	READA	Н	Η	L	Н	L	Н	٧	Н	V
Write	WRIT	Н	Н	L	Н	L	L	V	L	V
Write with Auto Pre-charge	WRITA	Н	Н	L	Н	L	L	V	Н	V
Bank Activate	ACT	Н	Н	L	L	Н	Н	V	V	V
Pre-charge Select Bank	PRE	Н	Н	L	L	Н	L	٧	L	Х
Pre-charge All Banks	PALL	Н	Ι	L	L	Н	L	X	Н	Х
(Ext.) Mode Register Set	EMRS	Н	Ι	L	L	L	L	V*	V	V
Auto Refresh	REF	Н	Н	L	L	L	Н	Χ	Χ	Х
Self refresh entry	SELF	Н	L	L	L	L	Н	Χ	Х	Х
Power Down Entry	PDEN	Н	L	Н	Х	Х	Х	Х	Х	Х
Power Down Entry	PDEN	Н	L	L	Н	Н	Н	Х	Х	Х
Power Down Exit	PDEX	L	Н	Н	Х	Х	Х	Х	Х	Х
TOWER DOWN EXIL	FUEX	L	Н	L	Н	Н	Н	Х	Х	Х

H = High level, L = Low level, X = High or Low level (Don't care), V = Valid data input

2. CKE Truth Table

Item	Command	Symbol	CKI	E	/CS	/RAS	/CAS	/WE	Addr.
item	Command	Symbol	n-1	n	/03	/RAS	ICAS	/VV⊏	Addi.
Any state	*Note1	-	Н	Н	V	V	V	V	V
All Bank Idle	Self Refresh Entry	SELF	Н	L	L	L	L	Η	Χ
Self Refresh	Self Refresh Exit	NOP	L	Н	L	Н	Н	Ι	X
Sell Reliesii	Sell Reliesh Exit	DESL	L	Η	Н	X	Х	Χ	X
All Bank Idle	Active or Precharge	DESL	Н	L	Н	Х	Χ	Χ	X
All Ballk lule	Power Down Entry	NOP	Н	L	L	Н	Н	Ι	X
Power Down	Power Down Exit	DESL	L	Н	Н	X	Χ	Χ	X
r ower bown	Tower Down Lxit	NOP	L	Н	L	Н	Н	Ι	X
Power Down	Maintain power down	-	L	L	Х	X	Χ	Χ	Χ
Self Refresh	Maintain self refresh	-	L	L	Х	X	Χ	Χ	Χ

H = High level, L = Low level, X = High or Low level (Don't care)

Note1: Must be legal commands as defined in the command truth table. And any state other than list above.

^{*} Please refers to the MRS, EMRS(1) & EMRS(2) setting

3. Operative Command Table

Current State	/CS	/R	/C	/W	Addr.	Command	Action
	Н	Х	Х	Х	Х	DESL	NOP
	L	Н	Н	Н	X	NOP	NOP
	L	Н	L	Н	BA/CA/A10	READ/READA	ILLEGAL (Note 1)
	L	Н	L	L	BA/CA/A10	WRIT/WRITA	ILLEGAL (Note 1)
Idle	L	L	Н	Н	BA/RA	ACT	Bank active,Latch RA
	L	L	Н	L	BA, A10	PRE/PREA	NOP(Note 3)
	L	L	L	Н	X	REF/SELF	Auto/Self refresh(Note 4)
	L	L	L	L	Op-Code, Mode-Add	MRS/EMRS(1)(2)	Mode register
	Н	Х	Х	Χ	Х	DESL	NOP
	L	Н	Н	Н	X	NOP	NOP
	L	Н	L	Н	BA/CA/A10	READ/READA	Begin read,Latch CA, Determine auto-precharge
Bank Active	L	Н	L	L	BA/CA/A10	WRIT/WRITA	Begin write,Latch CA, Determine auto-precharge
Active	L	L	Н	Н	BA/RA	ACT	ILLEGAL (Note 1)
	L	L	Н	L	BA/A10	PRE/PREA	Precharge/Precharge all
	L	L	L	Н	Х	REF/SELF	ILLEGAL (Note 1)
	L	L	L	L	Op-Code, Mode-Add	MRS/EMRS(1)(2)	ILLEGAL (Note 1)
	Н	Х	Χ	Χ	X	DESL	Row Active(Continue burst to end)
	L	Н	Н	Н	X	NOP	Row Active(Continue burst to end)
	L	Н	L	Н	BA/CA/A10	READ/READA	Burst Interrupt
Read	L	Н	L	L	BA/CA/A10	WRIT/WRITA	ILLEGAL(Note 1)
	L	L	Ι	Н	BA/RA	ACT	ILLEGAL (Note 1)
	L	L	Н	L	BA, A10	PRE/PREA	ILLEGAL (Note 1)
	L	L	L	Н	X	REF/SELF	ILLEGAL (Note 1)
	L	L	L	L	Op-Code, Mode-Add	MRS/EMRS(1)(2)	ILLEGAL (Note 1)
	Н	Х	Χ	Χ	Х	DESL	Write recovering (Continue burst to end)
	L	Н	Н	Н	Χ	NOP	Write recovering (Continue burst to end)
	L	Н	L	Н	BA/CA/A10	READ/READA	ILLEGAL(Note 1)
Write	L	Н	L	L	BA/CA/A10	WRIT/WRITA	Burst Interrupt
	L	L	Н	Н	BA/RA	ACT	ILLEGAL (Note 1)
	L	L	Н	L	BA, A10	PRE/PREA	ILLEGAL (Note 1)
	L	L	L	Н	X	REF/SELF	ILLEGAL (Note 1)
	L	L	L	L	Op-Code,	MRS/EMRS(1)(2)	ILLEGAL (Note 1)

3. Operative Command Table (Continued)

Current State	/CS	/R	/C	/W	Addr.	Command	Action
	Н	Х	X	Х	Х	DESL	Precharging (Continue burst to end)
	L	Н	Ι	Н	X	NOP	Precharging (Continue burst to end)
	L	Н	L	Н	BA/CA/A10	READ/READA	ILLEGAL (Note 1)
Read with	L	Н	L	L	BA/CA/A10	WRIT/WRITA	ILLEGAL (Note 1)
AP	L	L	Н	Н	BA/A10	ACT	ILLEGAL (Note 1)
	L	L	Н	L	BA/A10	PRE/PREA	ILLEGAL (Note 1)
	L	L	L	Н	Х	REF/SELF	ILLEGAL (Note 1)
	L	L	L	L	Op-Code, Mode-Add	MRS/EMRS(1)(2)	ILLEGAL (Note 1)
	Н	Х	Х	Х	Х	DESL	Write recover with auto precharge (Continue burst to end)
	L	Н	Η	Н	Х	NOP	Write recover with auto precharge (Continue burst to end)
	L	Н	L	Н	BA/CA/A10	READ/READA	ILLEGAL (Note 1)
Write with	L	Н	L	L	BA/CA/A10	WRIT/WRITA	ILLEGAL (Note 1)
AP	L	L	Н	Н	BA/RA	ACT	ILLEGAL (Note 1)
	L	L	Н	L	BA/A10	PRE/PREA	ILLEGAL (Note 1)
	L	L	L	Н	Х	REF/SELF	ILLEGAL (Note 1)
	L	L	L	L	Op-Code, Mode-Add	MRS/EMRS(1)(2)	ILLEGAL (Note 1)
	Н	Х	Х	Χ	Х	DESL	NOP(idle after tRP)
	L	Н	Н	Н	X	NOP	NOP(idle after tRP)
	L	Н	L	Н	BA/CA/A10	READ/READA	ILLEGAL (Note 1)
	L	Н	L	L	BA/CA/A10	WRIT/WRITA	ILLEGAL (Note 1)
Pre-charging	L	L	Н	Н	BA/RA	ACT	ILLEGAL (Note 1)
	L	L	Н	L	BA/A10	PRE/PREA	NOP(idle after tRP) (Note 3)
	L	L	L	Н	X	REF/SELF	ILLEGAL (Note 1)
	L	L	L	L	Op-Code, Mode-Add	MRS/EMRS(1)(2)	ILLEGAL (Note 1)
	Н	Χ	Χ	Χ	X	DESL	NOP(Row active after tRCD)
	L	Н	Н	Н	X	NOP	NOP(Row active after tRCD)
	L	Н	X X X X X H H H X H BA/CA/A10		READ/READA	ILLEGAL (Note 1)	
Row	L	Н	L	L	BA/CA/A10	WRIT/WRITA	ILLEGAL (Note 1)
Activating	L	L	Н	Н	BA/RA	ACT	ILLEGAL (Note 1)
	L	L	Н	L	BA/A10	PRE/PREA	ILLEGAL (Note 1)
	L	L	L	Н	Χ	REF/SELF	ILLEGAL (Note 1)
L = High lovel I	L	L	L	L	Op-Code, Mode-Add	MRS/EMRS(1)(2)	ILLEGAL (Note 1)

H = High level, L = Low level, X = High or Low level (Don't care), AP = Auto Pre-charge

3. Operative Command Table (Continued)

Current State	/CS	/R	/C	/W	Addr.	Command	Action
	Н	X	X	X	X	DESL	NOP (enter bank active after tWR)
	L	Ι	Ι	Ι	X	NOP	NOP (enter bank active after tWR)
	L	Н	L	Η	BA/CA/A10	READ	ILLEGAL (Note 1)
Write	L	Н	L	L	BA/CA/A10	WRIT/WRITA	New write, Determine AP
Recovering	L	L	Н	Н	BA/RA	ACT	ILLEGAL (Note 1)
	L	L	Н	L	BA/A10	PRE/PREA	ILLEGAL (Note 1)
	L	L	L	Н	Х	REF/SELF	ILLEGAL (Note 1)
	L	L	L	L	Op-Code, Mode-Add	MRS/EMRS(1)(2)	ILLEGAL (Note 1)
	Н	Χ	Χ	Χ	Х	DESL	NOP(idle after trec)
	L	Н	Н	Н	Х	NOP	NOP(idle after trec)
	L	Η	L	Η	BA/CA/A10	READ/READA	ILLEGAL (Note 1)
	L	Ι	Ш	L	BA/CA/A10	WRIT/WRITA	ILLEGAL (Note 1)
Refreshing	L	Ш	Ι	Ι	BA/RA	ACT	ILLEGAL (Note 1)
	L	L	Н	L	BA/A10	PRE/PREA	ILLEGAL (Note 1)
	L	L	L	Η	Х	REF/SELF	ILLEGAL (Note 1)
	L	L	L	L	Op-Code, Mode-Add	MRS/EMRS(1)(2)	ILLEGAL (Note 1)

H = High level, L = Low level, X = High or Low level (Don't care), AP = Auto Pre-charge

Note 1: ILLEGAL to bank in specified states;

Function may be legal in the bank indicated by Bank Address (BA), depending on the state of that bank.

Note 2: Must satisfy bus contention, bus turn around, and/or write recovery requirements.

Note 3: NOP to bank precharging or in idle state. May precharge bank indicated by BA.

Note 4: ILLEGAL of any bank is not idle.

4. Command Truth Table for CKE

Current State	С	KE	/CS	/R	/C	/W	Addr.	Action
	Н	Х	Х	Χ	Χ	Х	Χ	INVALID
	L	Н	Н	Χ	Χ	Х	Х	Exist Self-Refresh
	L	Н	L	Н	Н	Н	Х	Exist Self-Refresh
Self Refresh	L	Н	L	Н	Н	L	Χ	ILLEGAL
	L	Н	L	Н	L	Х	Χ	ILLEGAL
	L	Н	L	┙	Χ	X	Χ	ILLEGAL
	L	L	Х	Χ	Χ	X	Χ	NOP(Maintain self refresh)
	Н	Χ	Х	Χ	Χ	X	Χ	INVALID
	L	Н	Н	Χ	Χ	Х	X	Exist Power down
Both bank	L	Н	L	Н	Н	Н	Χ	Exist Power down
precharge	L	Н	L	Η	Η	L	Χ	ILLEGAL
power down	L	Н	L	Н	L	Χ	Χ	ILLEGAL
	L	Н	L	L	Χ	X	Χ	ILLEGAL
	L	L	Х	Χ	Χ	Х	Χ	NOP(Maintain Power down)
	Н	Н	Х	Χ	Χ	Х	Χ	Refer to function true table
	Н	L	Н	Χ	Χ	Х	Χ	Enter power down mode(Note 3)
	Н	L	L	Ι	Ι	Ι	X	Enter power down mode(Note 3)
	Н	L	L	Η	Н	L	X	ILLEGAL
All Banks Idle	Н	L	L	Η	L	Χ	Χ	ILLEGAL
	Н	L	L	L	Ι	Ι	RA	Row active/Bank active
	Н	L	L	┙	Ш	Ι	Χ	Enter self-refresh(Note 3)
	Н	L	L	┙	Ш	L	Op-Code	Mode register access
	Н	L	L	L	L	L	Op-Code	Special mode register access
	L	Х	Х	Χ	Χ	Χ	Χ	Refer to current state
Any state other than listed above	Н	Н	Х	X	X	Х	X	Refer to command truth table

H = High level, L = Low level, X = High or Low level (Don't care)

Notes 1: After CKE's low to high transition to exist self refresh mode. And a time of t_{RC}(min) has to be Elapse after CKE's low to high transition to issue a new command.

Notes 2: CKE low to high transition is asynchronous as if restarts internal clock.

Notes 3: Power down and self refresh can be entered only from the idle state of all banks.

5. Bank Selection Signal Table

Bank\Signal	BA0	BA1	BA2
Bank0	L	L	L
Bank1	Н	L	L
Bank2	L	Н	L
Bank3	Н	Н	L
Bank4	L	L	Н
Bank5	Н	L	Н
Bank6	L	Н	Н
Bank7	Н	Н	Н

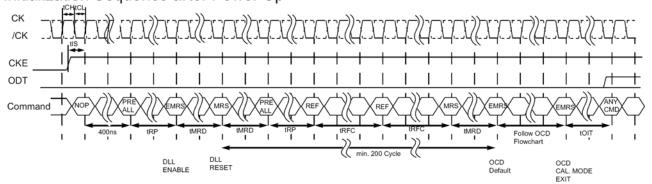
Note: H:VIH, L:VIL

Initialization

The following sequence is required for power-up and initialization and is shown in below Figure:

- 1. Apply power and attempt to maintain CKE below 0.2 * VDDQ and ODT at a low state (all other inputs may be undefined). To guarantee ODT off, VREF must be valid and a low level must be applied to the ODT pin.
- VDD, VDDL and VDDQ are driven from a single power converter output, and VTT is limited to 0.95 V max, and VREF tracks VDDQ/2 or
- Apply VDD before or at the same time as VDDL; Apply VDDL before or at the same time as VDDQ;
- Apply VDDQ before or at the same time as VTT & VREF. at least one of these two sets of conditions must be met.
- 2. Start clock (CK, /CK) and maintain stable power and clock condition for a minimum of 200 µs.
- 3. Apply NOP or Deselect commands & take CKE high.
- 4. Wait minimum of 400ns, then issue a Precharge-all command.
- 5. Issue Reserved command EMRS(2) or EMRS(3).
- 6. Issue EMRS(1) command to enable DLL. (A0=0 and BA0=1 and BA1=0)
- 7. Issue MRS Command (Mode Register Set) for "DLL reset". (A8=1 and BA0=BA1=0)
- 8. Issue Precharge-All command.
- 9. Issue 2 or more Auto-Refresh commands.
- 10. Issue a MRS command with low on A8 to initialize device operation. (Without resetting the DLL)
- 11. At least 200 clocks after step 8, execute OCD Calibration (Off Chip Driver impedance adjustment). If OCD calibration is not used, EMRS OCD Default command (A9=A8=A7=1) followed by EMRS(1) OCD Calibration Mode Exit command (A9=A8=A7=0) must be issued with other parameters of EMRS(1).
- 12. The DDR2 SDRAM is now initialized and ready for normal operation.

Initialization Sequence after Power Up



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Mode Register Definition Mode Register Set

The mode register stores the data for controlling the various operating modes of DDR2 SDRAM which contains addressing mode, burst length, /CAS latency, WR (write recovery), test mode, DLL reset and various vendor's specific opinions.

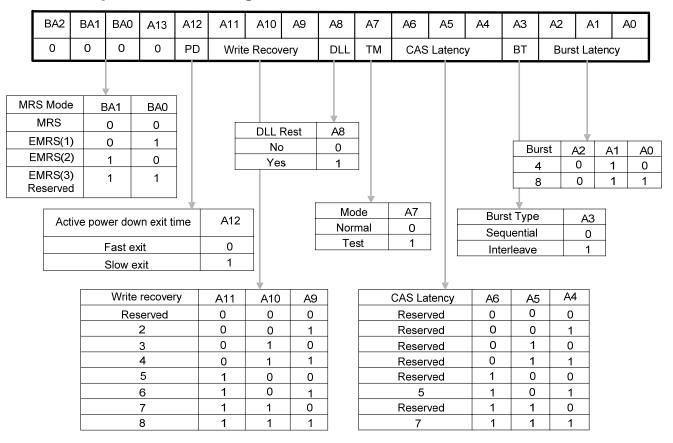
The defaults value of the register is not defined, so the mode register must be written after power up for proper DDR2 SDRAM operation. The mode register is written by asserting low on /CS, /RAS, /CAS, /WE and BA0/1. The state of the address pins A0-A12 in the same cycle as /CS, /RAS, /CAS, /WE and BA0/1 going low is written in the mode register.

Two clock cycles are requested to complete the write operation in the mode register. The mode register contents can be changed using the same command and clock cycle requirements during operating as long as all banks are in the idle state.

The mode register is divided into various fields depending on functionality. The burst length uses A0-A2, addressing mode uses A3, /CAS latency (read latency from column address) uses A4-A6. A7 is used for test mode. A8 is used for DDR reset. A9 ~ A11 are used for write recovery time (WR), A7 must be set to low for normal MRS operation. With address bit A12 two Power-Down modes can be selected, a "standard mode" and a "low-power" Power-Down mode.

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Address input for Mode Register Set



Burst Type (A3)

Burst Length	A2	A1	A0	Sequential Addressing	Interleave Addressing
	Х	0	0	0123	0123
4	Х	0	1	1230	1032
4	Х	1	0	2301	2301
	Х	1	1	3012	3 2 1 0
	0	0	0	01234567	01234567
	0	0	1	12345670	10325476
	0	1	0	23456701	23016745
8	0	1	1	34567012	32107654
0	1	0	0	45670123	45670123
	1	0	1	56701234	54761032
	1	1	0	67012345	67452301
	1	1	1	70123456	76543210

^{*}Page length is a function of I/O organization and column addressing

Write Recovery

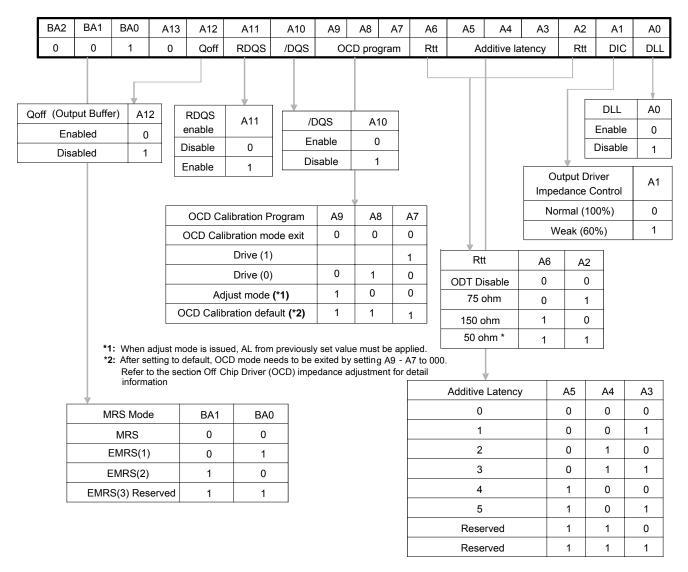
WR (Write Recovery) is for Writes with Auto-Precharge only and defines the time when the device starts pre-charge internally. WR must be programmed to match the minimum requirement for the analogue t_{WR} timing.

Power-Down Mode

Active power-down (PD) mode is defined by bit A12. PD mode allows the user to determine the active power-down mode, which determines performance vs. power savings. PD mode bit A12 does not apply to precharge power-down mode. When bit A12 = 0, standard Active Power-down mode or 'fast-exit' active power-down mode is enabled. The t_{XARD} parameter is used for 'fast-exit' active power-down exit timing. The DLL is expected to be enabled and running during this mode. When bit M12 = 1, a lower power active power-down mode or 'slow-exit' active power-down mode is enabled. The t_{XARDS} parameter is used for 'slow-exit' active power-down exit timing. The DLL can be enabled, but 'frozen' during active power-down mode since the exit-to-READ command timing is relaxed. The power difference expected between PD 'normal' and PD 'low-power' mode is defined in the IDD table.

Extended Mode Register Set EMRS(1)

The EMRS (1) is written by asserting low on /CS, /RAS, /CAS, /WE,BA1 and high on BA0 (The DDR2 should be in all bank pre-charge with CKE already prior to writing into the extended mode register.) The extended mode register EMRS(1) stores the data for enabling or disabling the DLL, output driver strength, additive latency, OCD program, ODT, DQS and output buffers disable, RQDS and RDQS enable. The default value of the extended mode register EMRS(1) is not defined, therefore the extended mode register must be written after power-up for proper operation. The mode register set command cycle time (t_{MRD}) must be satisfied to complete the write operation to the EMRS(1). Mode register contents can be changed using the same command and clock cycle requirements during normal operation when all banks are in pre-charge state.



Output Drive Strength

The output drive strength is defined by bit A1. Normal drive strength outputs are specified to be SSTL_18.

Programming bit A1 = 0 selects normal (100 %) drive strength for all outputs.

Programming bit A1 = 1 will reduce all outputs to approximately 60 % of the SSTL 18 drive strength.

This option is intended for the support of the lighter load and/or point-to-point environments.

Single-ended and Differential Data Strobe Signals

EM	IRS	St	robe Fund	tion Matri	х	Signals
A11 (/RDQS Enable)	A10 (/DQS Enable)	RDQS DM	/RDQS	DQS	/DQS	
0 (Disable)	0 (Enable)	DM	Hi-Z	DQS	/DQS	Differential DQS signal
0 (Disable)	1 (Disable)	DM	Hi-Z	DQS	Hi-Z	Single-ended DQS signal
1 (Enable)	0 (Enable)	RDQS	/RDQS	DQS	/DQS	Differential DQS signal
1 (Enable)	1 (Disable)	RDQS	Hi-Z	DQS	Hi-Z	Single-ended DQS signal

Output Disable (Qoff)

Under normal operation, the DRAM outputs are enabled during Read operation for driving data Qoff bit in the EMRS(1) is set to (0). When the Qoff bit is set to 1, the DRAM outputs will be disabled. Disabling the DRAM outputs allows users to measure IDD currents during Read operations, without including the output buffer current.

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Address input for Extended Mode Register Set EMRS(2) & EMRS(3)

EMRS (2) Programming: Reserved

ſ	BA2	BA1	BA0	A13	A12	A11	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0
I	0	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

^{* 1:} BA1 and BA0 must be programmed to 0 when setting the mode register during initialization.

EMRS (3) Programming: Reserved

BA2	BA1	BA0	A13	A12	A11	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0
0	1	1	0	0	0	0	0	0	0	0	0	0	0	0	0	0

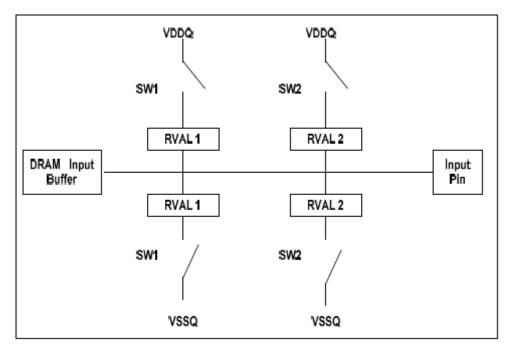
^{* 1:} BA1 and BA0 must be programmed to 0 when setting the mode register during initialization.

On-Die Termination (ODT)

ODT (On-Die Termination) is a new feature on DDR2 components that allows a DRAM to turn on/off termination resistance for each UDQ, LDQ, UDQS, UDQS, LDQS, LDQS, UDM and LDM signal via the ODT control pin for x16 configuration, where UDQS and LDQS are terminated only when enabled in the EMRS(1) by address bit A10 = 0.

The ODT feature is designed to improve signal integrity of the memory channel by allowing the DRAM controller to independently turn on/off termination resistance for any or all DRAM devices. The ODT function can be used for all active and standby modes. ODT is turned off and not supported in Self- Refresh mode.

ODT Function



Switch sw1 or sw2 is enabled by the ODT pin. Selection between sw1 or sw2 is determined by "Rtt (nominal)" in EMRS(1) address bits A6 & A2. Target Rtt = 0.5 * Rval1 or 0.5 * Rval2.

The ODT pin will be ignored if the EMRS(1) is programmed to disable ODT.

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Package Description: 84Ball-FBGA

Solder ball: Lead free (Sn-Ag-Cu)

